

Charge collection measurements with large passive array on CHESS-1 chip irradiated with neutrons

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- experimental setup and first results shown at the last meeting

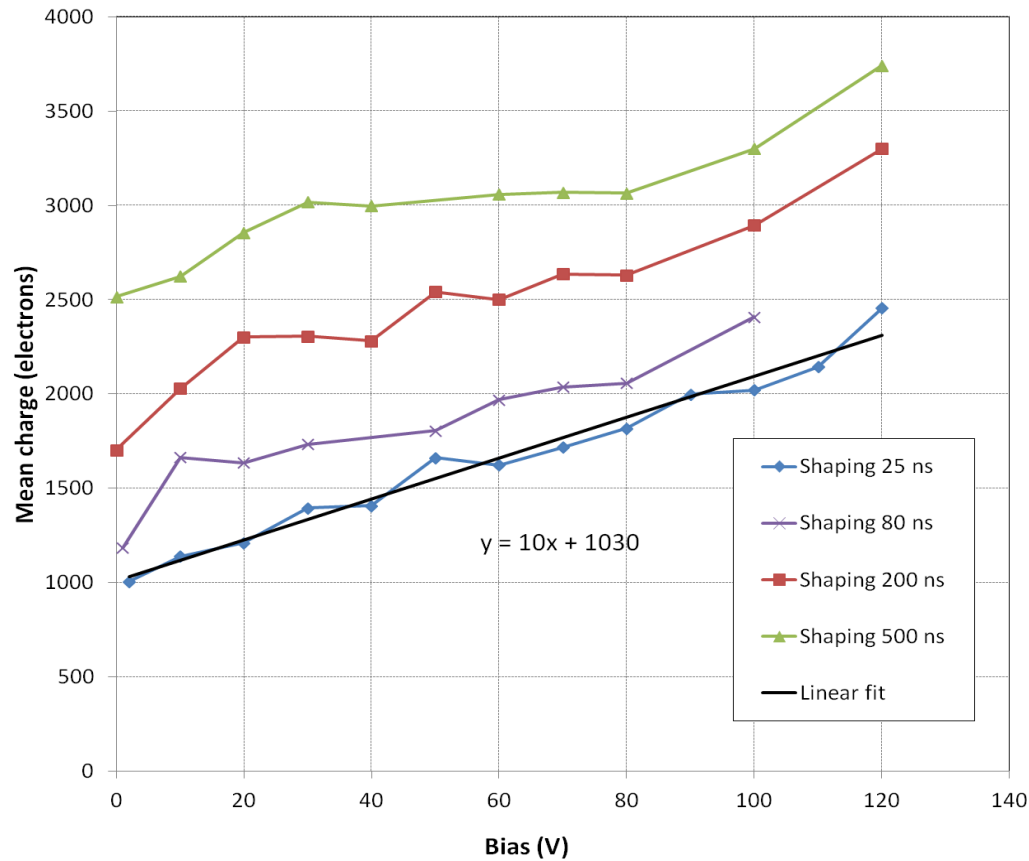
<https://indico.desy.de/getFile.py/access?contribId=4&sessionId=0&resId=0&materialId=slides&confId=11374>

- ➔ measure collected charge with large passive array with Sr90
- ➔ measure with charge sensitive amplifier and custom made shaper with selectable shaping times

- in this presentation:

- measurements before irradiation up to 120 V
- first results with device irradiated in reactor with neutrons to $\Phi_{eq} = 2e14 \text{ n/cm}^2$

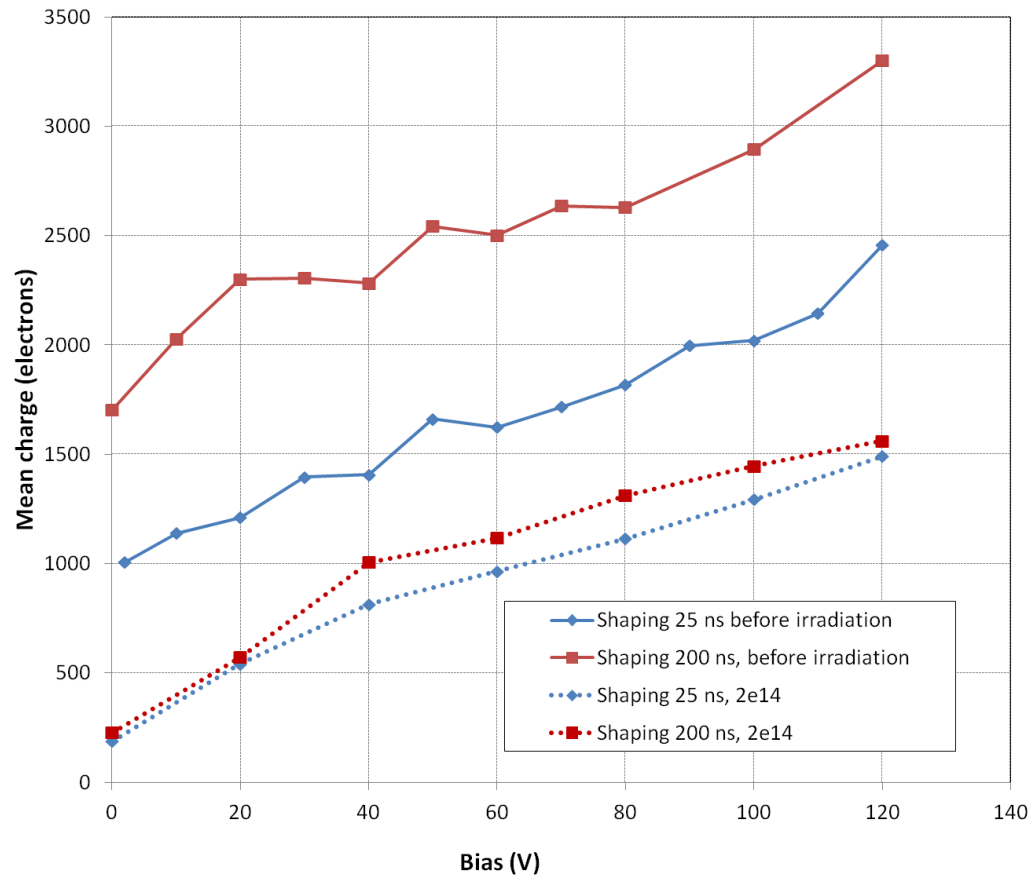
Before irradiation



- measurements extended up to bias of 120 V
- relation at 25 ns: **Mean charge = 1030 el + 10 el/V**

Irradiated device

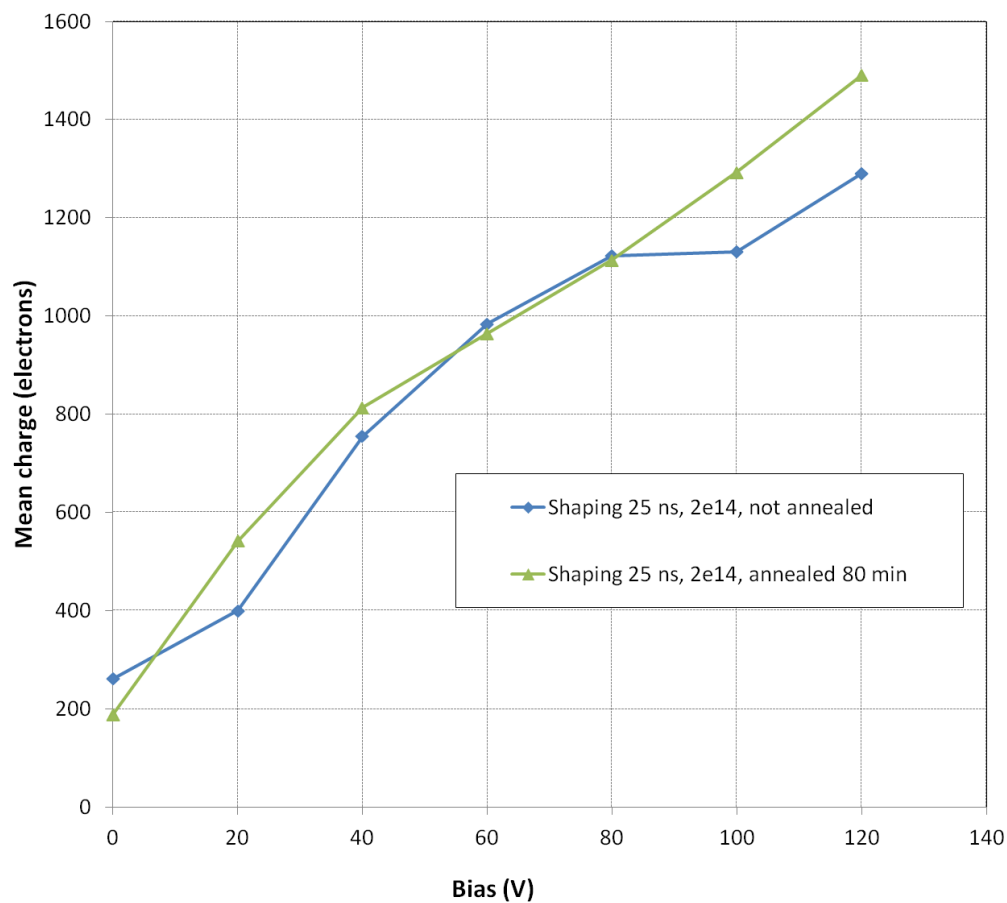
- sample irradiated in TRIGA reactor in Ljubljana to equivalent fluence $\Phi_{eq} = 2e14 \text{ n/cm}^2$
- annealed at 60 C for 80 minutes



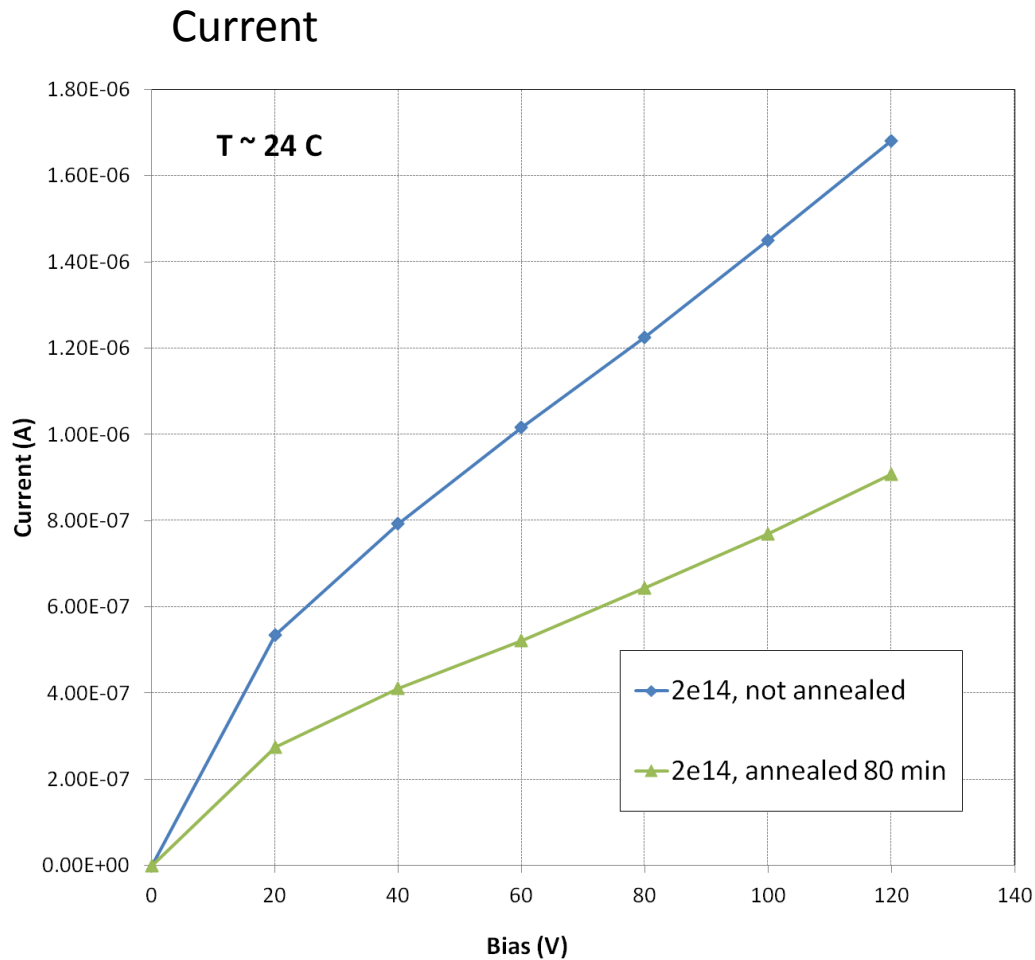
- ➔ at 25 ns shaping about 35 % less charge measured after irradiation at high voltage
- ➔ small dependence on shaping time after irradiation → small contribution from diffusion

Irradiated device

- small effect of annealing on measured charge



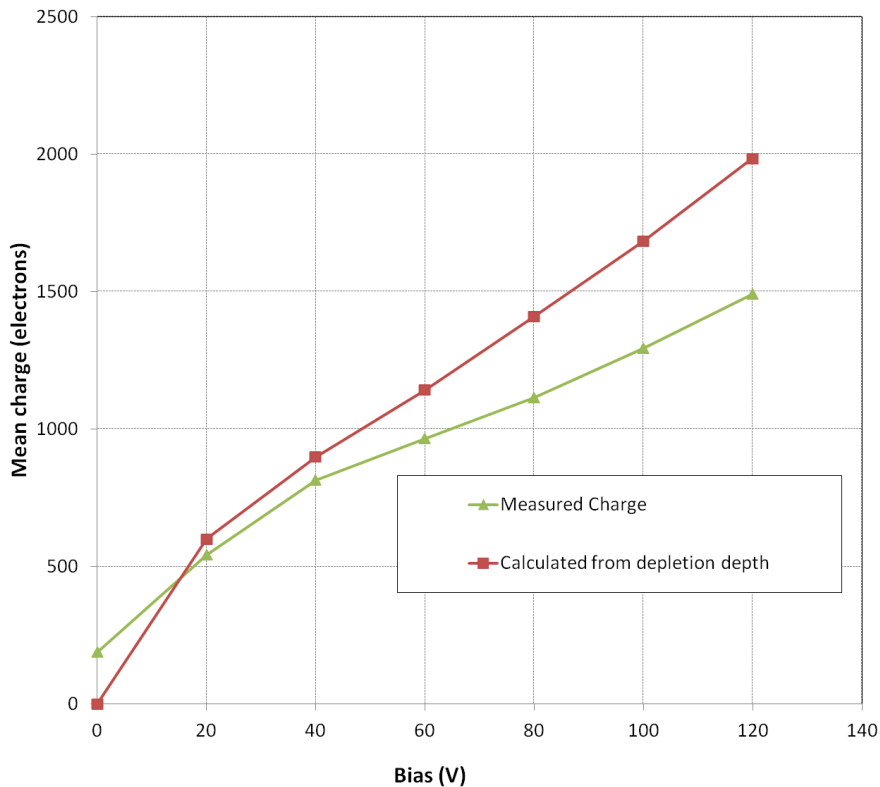
Irradiated device



Irradiated device

- from current after annealing depleted depth can be estimated: $w = I/\alpha\Phi S$
 $\alpha = 4\text{e-}17 \text{ A/cm}$, $S = 2 \text{ mm}^2$, correction factor 0.7 because current measured at $T = 24 \text{ C}$

➔ charge can be estimated from depleted depth assuming mean charge $100 \text{ el}/\mu\text{m}$



Summary :

Before irradiation

- at 25 ns shaping: **Mean charge = 1030 el + 10 el/V**
- collected charge increases with longer shaping times

After irradiation with neutrons $\Phi_{eq} = 2e14 \text{ n/cm}^2$

- at 25 ns shaping about 35% less charge measured at high bias voltage
- small dependence on shaping time → small contribution from diffusion
- measured charge agrees with estimation from depleted depth calculated from leakage current